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DATE MAILED: 07/03/2006

APPLICATION NO.	FI	LING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO	
10/743,578 12/22/2003		12/22/2003	Sang Deok Kim	29936/39886	7996	
4743	7590	07/03/2006		EXAMINER		
	•	STEIN & BORUN	BOOTH, RICHARD A			
SEARS TO		VE, SUITE 6300	ART UNIT	PAPER NUMBER		
CHICAGO,	IL 6060	6	2812			

Please find below and/or attached an Office communication concerning this application or proceeding.

		Applicati	on No.	Applicant(s)				
		10/743,5	78	KIM, SANG DEOK				
Off	fice Action Summary	Examine		Art Unit				
		Richard A	. Booth	2812				
The fi	NAILING DATE of this communicat	ion appears on th	e cover sheet with the	correspondence add	Iress			
A SHORTEN WHICHEVE - Extensions of t after SIX (6) M - If NO period fo - Failure to reply Any reply recei	IED STATUTORY PERIOD FOR IS LONGER, FROM THE MAIL me may be available under the provisions of 30 DNTHS from the mailing date of this communic reply is specified above, the maximum statuto within the set or extended period for reply will, yed by the Office later than three months after the erm adjustment. See 37 CFR 1.704(b).	ING DATE OF TI 7 CFR 1.136(a). In no evation. Ty period will apply and we by statute, cause the apply	HIS COMMUNICATIO ent, however, may a reply be ti till expire SIX (6) MONTHS from dication to become ABANDONI	N. mely filed n the mailing date of this cor ED (35 U.S.C. § 133).				
Status								
2a) ☐ This ad 3) ☐ Since	nsive to communication(s) filed oction is FINAL . 2b)[this application is in condition for in accordance with the practice of	☐ This action is rallowance except	for formal matters, pr		merits is			
Disposition of (Claims							
4a) Of 5) ☐ Claim(6) ☑ Claim(7) ☐ Claim(8) ☐ Claim(Application Pap 9) ☐ The spont of the drawn of the d	s) 1-3,5-9,11 and 12 is/are pendithe above claim(s) is/are vers is/are allowed. s) is/are allowed. s) 1-3,5-9,11 and 12 is/are rejectes. join is/are objected to. s) is/are objected to. s) are subject to restriction ers. ecification is objected to by the Examing(s) filed on is/are: a) int may not request that any objection ement drawing sheet(s) including the thor declaration is objected to by	vithdrawn from coned. and/or election reconed. caminer. accepted or by the tothe drawing(s) is correction is required.	nsideration. equirement. objected to by the be held in abeyance. Seed if the drawing(s) is objected to be objected.	e 37 CFR 1.85(a). Djected to. See 37 CFI				
Priority under 3	5 U.S.C. § 119							
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No. 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 								
2) Notice of Draf 3) Information Di	rences Cited (PTO-892) sperson's Patent Drawing Review (PTO- sclosure Statement(s) (PTO-1449 or PTC lail Date		4) Interview Summary Paper No(s)/Mail D 5) Notice of Informal I 6) Other:	ate	-152)			

DETAILED ACTION

Continued Examination Under 37 CFR 1.114

A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on 5/2/06 has been entered.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 1-3, 5-9, and 11-12 are rejected under 35 U.S.C. 103(a) as being unpatentable over Admitted prior art in view of Rossman, U.S. 2005/0032382.

Admitted prior art discloses providing a semiconductor substrate in which a gate electrode pattern is formed; and forming an interlayer insulator film in order to bury the gate electrode pattern (see fig. 1 and paragraph 0002 of specification).

Admitted prior art does not expressly disclose forming the interlayer insulator film including a multi-layered oxide film by performing multiple simultaneous deposition-and-

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etch processes, wherein a deposition-and-etch rate of a subsequent deposition-and-etch process is decreased relative to a preceding deposition-and-etch process.

Rossman discloses forming a first HDP oxide film using simultaneous depositionand-etch processes of a first rate, where the etch process is sputtering, followed by
forming a second HDP oxide film using simultaneous deposition-and-etch processes of
a second rate, whereby the second rate is less than the first rate (see, for example,
claim 53). In view of this disclosure, it would have been obvious to one of ordinary skill
in the art at the time the invention was made to modify the process of the admitted prior
art so as to form HDP oxide films using the process described in Rossman to bury the
gate electrode because in such a way gap-filling characteristics can be increased at
desired times.

With respect to the particular deposition to etch rate and the refractive index of the interlayer insulator film, it would have been obvious to one of ordinary skill in the art at the time the invention was made to determine through routine experimentation the optimum deposition to etch rate ratio and refractive index based upon a variety of factors including the desired density of the material and such limitations would not lend patentability to the instant application absent a showing of unexpected results.

Response to Arguments

Applicant's arguments with respect to claims 1-3, 5-9, and 11-12 have been considered but are moot in view of the new ground(s) of rejection.

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Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Richard A. Booth whose telephone number is (571) 272-1668. The examiner can normally be reached on Monday-Thursday from 7:30-6:00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Michael Lebentritt can be reached on (571) 272-1873. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or \$71-272-1000.

Richard A√Booth Primary Examiner Art Unit 2812

June 24, 2006